

# SEARCHED

Class	Sub.	Date	Exmr.
530	399	8/6/01	SLW
536	23.51		
435	35		
536	23.1		
435	320.1		
435	325		
435	252.3		
updated		10/2/02	SLW
530	300		
	324		
	388.22		
	326		
424	85.1		
	178.1		
	1.11		
514	2		

# SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	Date	Exmr.
SEQ ID #1 with X-ray (enclosed) Issued - Patent # Gen Enable, N-Gene seq-36, EST.	8/6/01	SLW
BLAST alignment SEQ ID NO:1	8/7/01	SLW
Inventors, PALM, EAST	8/7/01	SLW
Text Search SEQ ID NO:1 USPAT, EPO, Derwent, Biosis	8/8/01	SLW
Interference STIC-Search SEQ ID NO:2	1/29/02	SLW
SEQ ID NO:5	2/3/02	SLW
updated SEQ ID NO:1, 2 visual inspection of residue 1.18	3/30/02	SLW
updated Interference STIC-SEQ ID NO:2	10/18/02	SLW
	10/17/02	SLW

# INTERFERENCE SEARCHED

Class	Sub.	Date	Exmr.
Interfer. STIC databases	SEQ ID NO:2, 5	1/29/02	SLW
Interference STIC databases	SEQ ID NO:2	10/17/02	SLW
530	300	10/18/02	SLW
	324		
	319		
424	85.1		
	178.1		
514	2		